

**BUFFER GATE DRIVER IC****Features**

- High peak output current > 10A
- Low propagation delay time
- Negative turn off bias can be applied to  $V_{EE}$  using an external supply
- Two output pins permit to choose different  $R_{on}$  and  $R_{off}$  resistors.
- Low supply current
- Undervoltage lockout
- Continuous 'on' capability
- Suitable for high power inverter applications in conjunction with an external pre-driver
- Lead-Free, RoHS Compliant
- Automotive qualified

**Description**

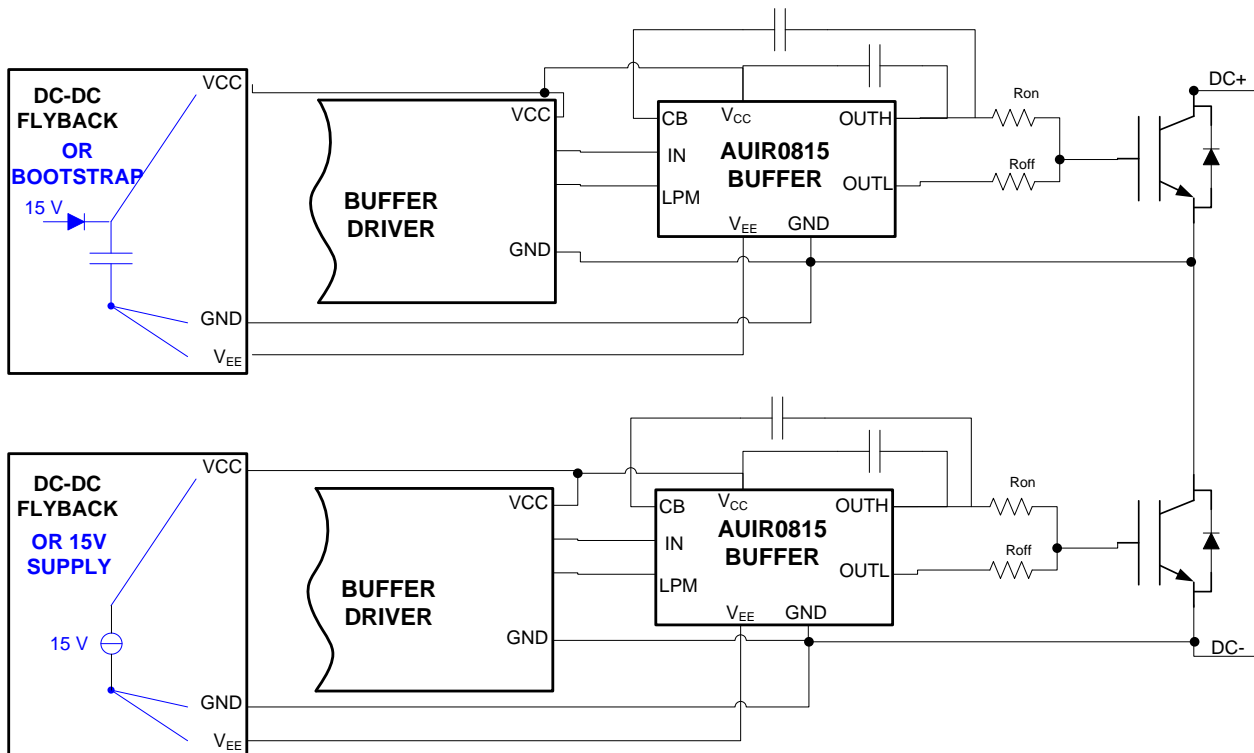
The AUIR0815 buffer gate driver family, in conjunction with a pre-driver stage, is suited to drive a single half bridge in power switching applications. These buffer gate drivers incorporate the ability to enter into a low quiescent current mode.

**Product Summary**

$V_{CC}-GND$	10V to 30V
$GND-V_{EE}$	-1V to 20V
$V_{CC}-V_{EE}$	10V to 30V
$I_{O\ drive}$	> 10A

**Package**

8 Pin SOIC

**Typical connection**

**Qualification Information<sup>†</sup>**

<b>Qualification Level</b>		Automotive (per AEC-Q100 <sup>††</sup> )	
		Comments: This family of ICs has passed an Automotive qualification. IR's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
<b>Moisture Sensitivity Level</b>		SOIC8N	MSL2 <sup>†††</sup> 260°C (per IPC/JEDEC J-STD-020)
<b>ESD</b>	Machine Model	Class M1 (Pass +/-100 V) (per AEC-Q100-003)	
	Human Body Model	Class H1B (+/-1000V) (per AEC-Q100-002)	
	Charged Device Model	Class C4 (Pass +/-1000V) (per AEC-Q100-011)	
<b>IC Latch-Up Test</b>		Class II, Level A (per AEC-Q100-004)	
<b>RoHS Compliant</b>		Yes	

† Qualification standards can be found at International Rectifier's web site <http://www.irf.com/>

†† Exceptions to AEC-Q100 requirements, if any, are noted in the qualification report.

††† Higher MSL ratings may be available for the specific package type listed here. Please contact your International Rectifier sales representative for further information.

## Absolute Maximum Ratings

Absolute maximum ratings indicate sustained limits beyond which permanent damage to the device may occur. These are stress ratings only, functional operation of the device at these or any other condition beyond those indicated in the “Recommended Operating Condition” is not implied. Exposure to absolute maximum-rated conditions for extended periods may affect device reliability. All voltage parameters are absolute voltages referenced to GND unless otherwise stated in the table. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions.

Symbol	Definition	Min	Max	Units
GND	to Vcc	-37	0.3	V
V <sub>EE</sub>	To Vcc	-37	0.3	V
V <sub>IN</sub>	Logic input voltage to Vcc	- 40	0.3	V
VB	Vbootstrap to OUTPUT	-0.3	5.5	V
LPM	LPM voltage to Vcc	- 40	0.3(*)	V
V <sub>OUTH</sub>	OUTH Output voltage	V <sub>CC</sub> -37	V <sub>CC</sub> + 0.3	V
V <sub>OUTL</sub>	OUTL output voltage	V <sub>EE</sub> -0.2	V <sub>CC</sub> + 0.3	V
P <sub>D</sub>	Package power dissipation @ T <sub>A</sub> ≤ 25 °C	—	1	W
R <sub>thJA</sub>	Thermal resistance, junction to ambient	—	80	°C/W
T <sub>J</sub>	Junction temperature	-40	150	°C
T <sub>S</sub>	Storage temperature	-55	150	°C
T <sub>L</sub>	Lead temperature (soldering, 10 seconds)	—	300	°C

(\*) LPM is allowed to settle to an higher voltage than specified providing a current limitation of 10uA

## Recommended Operating Conditions

For proper operation the device should be used within the recommended conditions. All voltage parameters are absolute voltages referenced to GND unless otherwise stated in the table

Symbol	Definition	Min.	Max.	Units
V <sub>CC-GND</sub>	Gate driver positive supply voltage	6(*)	30	V
GND- V <sub>EE</sub>	Gate driver negative supply voltage. V <sub>EE</sub> is Shorted to GND in case of single supply operation	-1	15	
V <sub>CC- V<sub>EE</sub></sub>	Total supply voltage	10	30	
V <sub>OUTH</sub>	OUTH Output voltage	V <sub>CC</sub> -30	V <sub>CC</sub>	
V <sub>OUTH - V<sub>EE</sub></sub>	Voltage difference between OUTH and V <sub>EE</sub>	-5	—	
V <sub>IN</sub>	Logic input voltage (IN and LPM)	V <sub>CC</sub> -35	V <sub>CC</sub>	
Cboot	OUTPUT pull up boot capacitor	10	20	nF
Ron	OUTH series resistor to gate	1.5	20	Ohm
Roff	OUTL series resistor to gate	1.5	20	Ohm
Cs	Snubber capacitor between OUTH and VCC	10	24	nF
PWoff	IN 'low' pulse width (**)	2		usec

(\*)When 3V < V<sub>CC-GND</sub> < V<sub>CC-GND\_MIN</sub> 30 Ohm max resistance pulls down OUTL to V<sub>EE</sub> while OUTH is in HiZ. Guaranteed by design.

(\*\*) V<sub>CC-V<sub>EE</sub></sub><12V, see also “Role of Cboot and Effect of Short ‘Off’ Pulses” chapter.

**Static Electrical Characteristics**

$V_{CC-GND} = 15V$ ;  $GND-V_{EE} = 5V$ ; 15nF connects CB to OUTH; 22nF connects  $V_{CC}$  to OUTH;  $-40^\circ C < T_A < 125^\circ C$  unless otherwise specified.

Symbol	Definition	Min	Typ	Max	Units	Test Conditions
$V_{CCUV+}$	$V_{CC-GND}$ supply undervoltage positive going threshold	10.2	11.7	12.8	V	LPM=HIN=1= $V_{CC}$ $V_{EE}=GND$ ; OUTH pulled to $V_{CC}-2V$ with 100mA current limitation
$V_{CCUV-}$	$V_{CC-GND}$ supply undervoltage negative going threshold	9.6	10.5	11.4		
$V_{CCUVH}$	$V_{CC-GND}$ supply undervoltage lockout hysteresis	0.5	1.2	—		
$V_{BUV}$	Vbootstrap undervoltage (*)	—	4	—	V	
$I_{QGG}$	GND supply current	—	—	60	$\mu A$	IN=X; LPM=X
$I_{QESW}$	$V_{EE}$ supply current, IN switching	2	4	10	mA	IN switches at 10kHz 50% duty cycle; LPM=1
$I_{QEE0}$	$V_{EE}$ supply current, IN=0	—	—	8.0	mA	steady state with IN=0 and LPM=1
$I_{QEE025}$	$V_{EE}$ supply current, IN=0	—	—	6.5	mA	steady state with IN=0 and LPM=1, $T=25^\circ C$
$I_{QEE1}$	$V_{EE}$ supply current, IN=1	—	—	3	mA	steady state with IN=1 and LPM=1
$I_{QEELQ0}$	$V_{EE}$ supply current, LPM=0, IN=0	—	—	2	mA	steady state with IN=0 and LPM=0
$I_{QEELQ1}$	$V_{EE}$ supply current, LPM=0, IN=1	—	—	1.5	mA	steady state with IN=1 and LPM=0
$I_{QEEUV}$	$V_{EE}$ supply current, $V_{CC} < V_{CCUV-}$	—	—	1.8	mA	steady state with IN=X, LPM=X, $V_{CC} < V_{CCUV-}$
$I_{QOUTL1}$	Current flowing into OUTL	—	—	1.5	$\mu A$	IN=1; LPM=1; OUTL-GND=15V; OUTH disconnected
$I_{QB}$	Current into CB pin	—	—	1	mA	IN=1; LPM=1; CB-OUTH=5V
$I_{QOUTH0}$	Current flowing out from OUTH	—	—	3.5	mA	steady state with IN=0 and LPM=1, $V(OUTH)=V_{EE}$ , OUTL disconnected
$I_{BOUTH}$	Current flowing out from CB, bootstrap discharged	—	20	40	mA	steady state, CB shorted to OUTH, IN=0 and LPM=1, $V(OUTH)=V_{EE}$ , OUTL disconnected
$I_{OUTH+}$	OUTH high short circuit pulsed current	10	—	—	A	10A current pulse with $PW < 10\mu sec$
$I_{OUTL-}$	OUTL low short circuit pulsed current	10	—	—	A	

(\*)When  $CB-OUTH < V_{BUV}$  the power nmos pulling up OUTH is turned off. The high level on OUTH is kept by a parallel PMOS (see also block diagram).

**Pins: IN, LPM**

$V_{CC-GND} = 15V$ ;  $GND-V_{EE} = 5V$ ; 15nF connects CB to OUTH; 22nF connects  $V_{CC}$  to OUTH;  $-40^\circ C < T_A < 125^\circ C$  unless otherwise specified.

Symbol	Definition	Min	Typ	Max	Units	Test Conditions
$V_{INH_{VCC}}$	Logic "1" IN input voltage to $V_{CC}$	-3.5	-2.5	-1.0	V	$V_{CC-GND} > V_{CCUV-}$
$V_{INL_{VCC}}$	Logic "0" IN input voltage to $V_{CC}$	-5.5	-4.5	-3.5		
$V_{INhis}$	Logic IN input hysteresis	1	2	3.3		
$V_{LPMH_{VCC}}$	Logic "1" LPM input voltage to $V_{CC}$	-3	-2.5	-1.4	V	$V_{CC-GND} > V_{CCUV-}$
$V_{LPL_{VCC}}$	Logic "0" LPM input voltage to $V_{CC}$	-3.8	-3	-2.5		
$V_{LPMhis}$	Logic LPM input hysteresis	0.25	-	1.8		
$I_{IN15}$	Current flowing out from IN when $V_{CC-IN}=15V$	40	90	180	$\mu A$	IN=GND
$I_{LPM15}$	Current flowing out from LPM $V_{CC-LPM}=15V$	10	25	50	$\mu A$	LPM=GND

**Pins: OUTH,OUTL**

$V_{CC}-GND=15V$ ;  $GND-V_{EE}=5V$ ; 15nF connects CB to OUTH; 22nF connects  $V_{CC}$  to OUTH;  $-40\text{ }^{\circ}\text{C} < T_A < 125\text{ }^{\circ}\text{C}$  unless otherwise specified.

Symbol	Definition	Min	Typ	Max	Units	Test Conditions
Rup_OUTH25	Rdson pull up transistor OUTH	—	90	120	mOhm	10A current pulse with PW<10usec $T_A=25^{\circ}\text{C}$
Rdw_OUTL25	Rdson pull down transistor OUTL	—	180	240		
Rup_OUTH	Rdson pull up transistor OUTH	—	—	180		10A current pulse with PW<10usec
Rdw_OUTL	Rdson pull down transistor OUTL	—	—	320		
$I_{PMOS}$	OUTH Pull up current when bootstrap cap is discharged	5	20	30	mA	IN=1 LPM=1, CB-OUTH=2.5V, OUTH pulled to VCC-1.5V

**AC Electrical Characteristics**

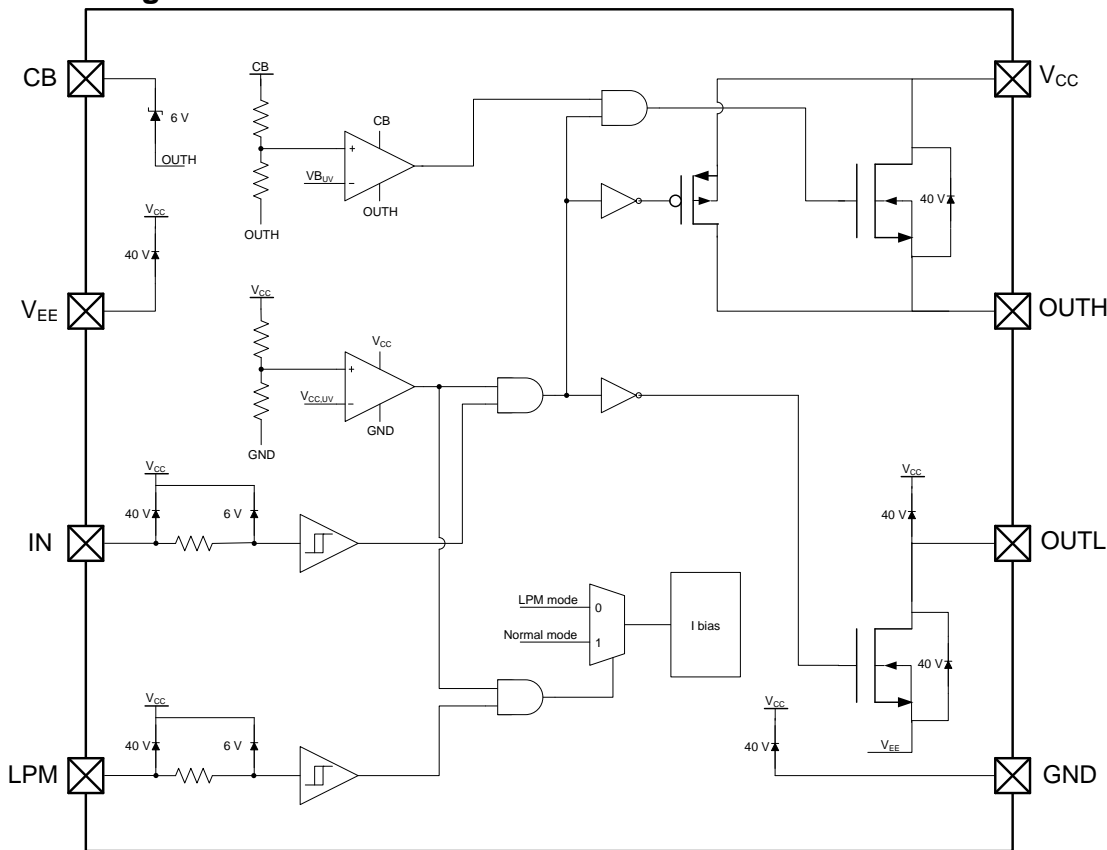
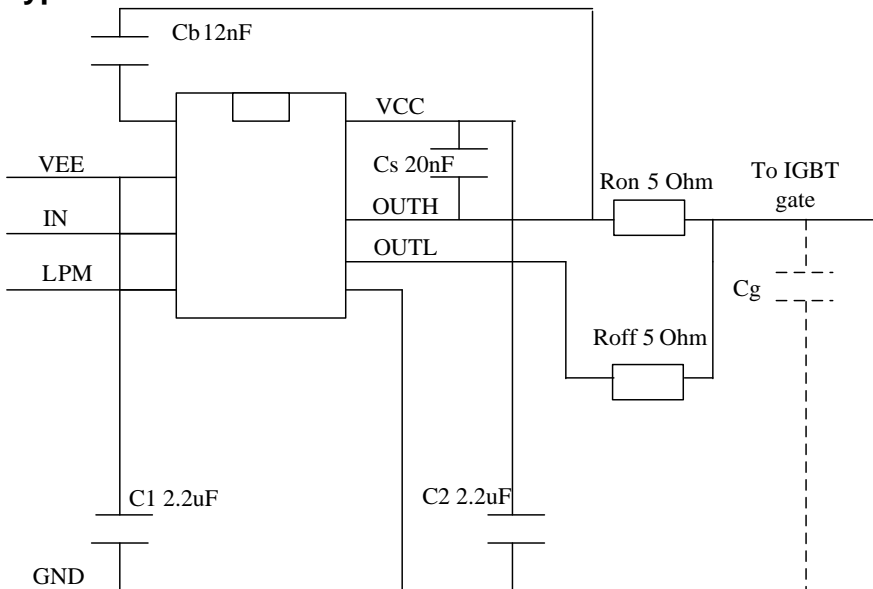
$V_{CC}-GND=15V$ ;  $GND-V_{EE}=5V$ ; 15nF connects CB to OUTH; 22nF connects  $V_{CC}$  to OUTH ; $R_{on}=5\text{ Ohm}$  ,  $R_{off}=5\text{ Ohm}$  ,  $C_{LOAD}=100\text{ nF}$  ,  $-40\text{ }^{\circ}\text{C} < T_A < 125\text{ }^{\circ}\text{C}$  unless otherwise specified.

Propagation is from INPUT at GND or  $V_{CC}$  to 10% voltage variation of output

RISE FALL TIME is delay from 10% to 90% output swing

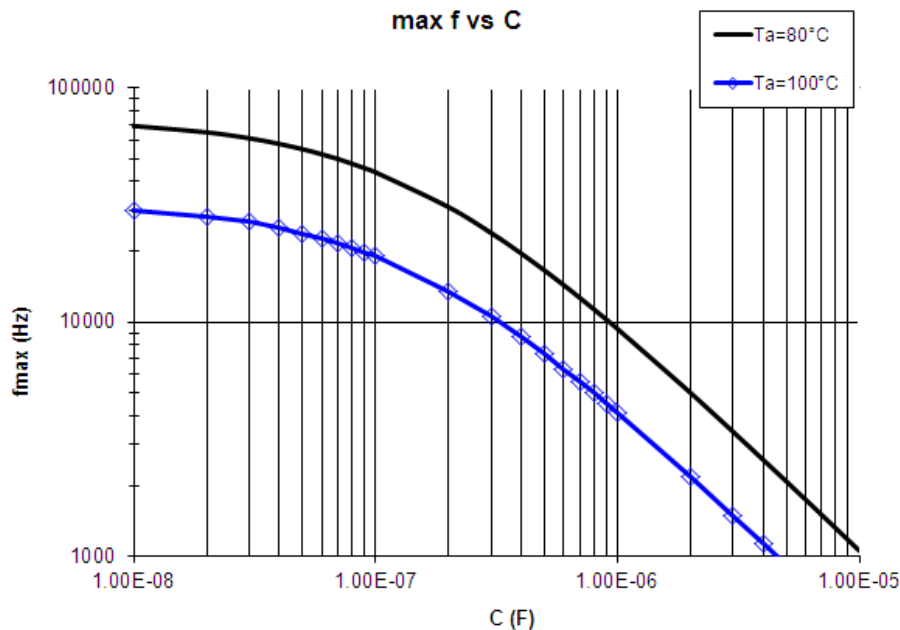
Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
$t_{on}$	Turn on propagation delay IN-OUTH	—	250	400	ns	
$t_{off}$	Turn off propagation delay IN-OUTL	—	250	350		
$t_r$	Turn on rise time OUTH	—	—	260		
$t_f$	Turn off fall time OUTL	—	—	150		
$t_{rLQ}$	Turn on rise time OUTH in Low Quiescent Current Mode	—	—	1000	ns	$V_{EE}=GND$ , LPM=0, $V_{CC}$ rises above $V_{CCUV+}$ ; $C_{LOAD}=100\text{ nF}$ $R_{on}=5\text{ Ohm}$ , $R_{off}=5\text{ Ohm}$
$t_{fLQ}$	Turn off fall time OUTL in Low Quiescent Current Mode	—	—	1000	ns	$V_{EE}=GND$ , LPM=0, $V_{CC}$ falls below $V_{CCUV+}$ ; $C_{LOAD}=100\text{ nF}$ $R_{on}=5\text{ Ohm}$ , $R_{off}=5\text{ Ohm}$
$PW_{ON}$	IN high pulse width (*)	500	—	—	ns	No $C_{LOAD}$ , $-40\text{ }^{\circ}\text{C} < T_A < 125\text{ }^{\circ}\text{C}$
$PW_{OFF}$	IN low pulse width (*)	500	—	—	ns	No $C_{LOAD}$ , $-40\text{ }^{\circ}\text{C} < T_A < 125\text{ }^{\circ}\text{C}$

(\*) IN pulse width lower than  $PW_{ONMIN}$  ( $PW_{OFFMIN}$ ) min can be filtered

**Block Diagram:**

**Typical connection**


It is recommended:

- to have a capacitance  $C_s$  connected between OUTH and VCC to limit  $dv/dt$  in OUTH node (mandatory if  $V_{cc}-V_{ee}>15V$ ). See Recommended Operating Condition for  $C_s$  value.
- to avoid the condition with OUTH directly shorted to OUTL
- Use ceramic capacitor for C1 and C2 with value  $> 20 \cdot C_{gate}$

**Application Information And Additional Details**


Recommended maximum switching frequency when driving a capacitance C with a 3 Ohm external resistor.

$C_s=20\text{nF}$  is connected between OUTH and Vcc.

$V_{CC}-V_{EE}=24\text{V}$ .

**Truth Table**

Vcc	IN	LPM	Status/Comment
$V_{CC-GND\_MIN}$ to $V_{CCUV}$	-	-	OUTL = $V_{EE}$ , OUTH in HiZ → IGBT OFF; Low Quiescent Current Mode is active.
$V_{CCUV}$ to 30V	0	1	OUTL = $V_{EE}$ , OUTH in HiZ → IGBT OFF;
$V_{CCUV}$ to 30V	1	1	OUTL in HiZ, OUTH = Vcc → IGBT ON;
$V_{CCUV}$ to 30V	0	0	OUTL = $V_{EE}$ , OUTH in HiZ → IGBT OFF; Low Quiescent Current Mode is active
$V_{CCUV}$ to 30V	1	0	OUTL in HiZ, OUTH = Vcc → IGBT ON; Low Quiescent Current Mode is active

**Role of Cboot and Effect of Short ‘Off’ Pulses**

Cboot capacitance, connected between OUTH and CB acts as a bootstrap supplying the circuitry driving the low  $r_{ds(on)}$  ( $R_{up\_OUTH}$ ) pull-up nmos connected between Vcc and OUTH.

In the application, when IN is low, OUTH is tied to VEE and Cboot is charged to around 6V.

At IN rising the pullup nmos is turned on and it is able to provide a low impedance path between VCC and OUTH.

Maintaining IN high, Cboot get discharged and therefore the pull-up nmos is turned off but the parallel pmos (see Block diagram) remains on maintaining OUTH tied to VCC.

Cboot discharge rate is  $I_{QB}/C_{boot}$ , typically it takes about 250 usec for a complete discharge.

In case Cboot get discharged, the subsequent off pulse width must be long enough to recharge Cboot above the bootstrap under-voltage threshold  $V_{B_{UV}}$ . to allow the turn on of the pull-up nmos when IN rises again. Short Off pulse width can lead to a situation, after the pulse, with too low IGBT Vge voltage, worst case is for low values of  $V_{CC}-V_{EE}$ , that is just above  $V_{CCUV}$ .. Even though it is allowed, at higher values of  $V_{CC}-V_{EE}$ , to reduce the off pulse width below  $PW_{off\ min}$ , it is suggested to keep the off pulse width above 1usec in every working condition.

## Examples of system schematics with HVIC

This section shows how IR High Voltage IC (HVIC) gate drivers can be used to drive the AUIR0815.

All the examples refer to an inverter leg, showing the floating voltage sources  $V_{ch}$  and  $V_{eh}$  to supply the high side AUIR0815 and  $V_{cl}$  and  $V_{el}$  to supply the low side AUIR0815.

All the examples show 7V floating voltage sources to provide a negative  $V_{ge}$  to turn off each IGBT. In case a negative  $V_{ge}$  is not required these voltage sources can be replaced with a short circuit.

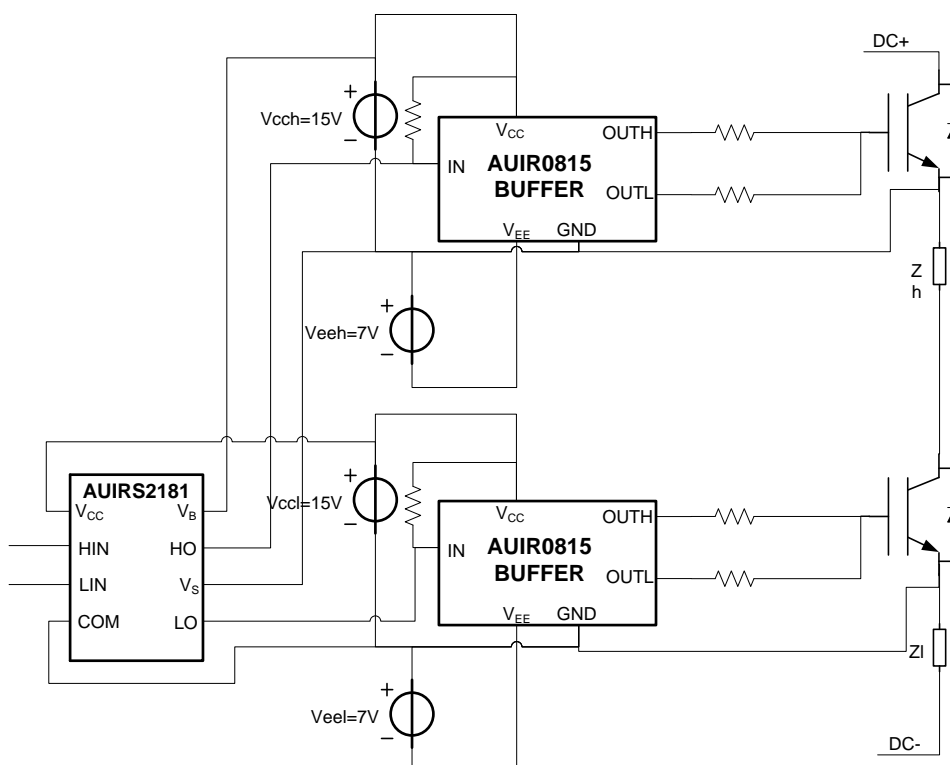
In case of three phase inverters, each of the high side AUIR0815 must have separated and isolated voltage supplies.

Only one DC power supply can be shared for the low sides AUIR0815 supplies (to be connected between AUIR0815  $V_{cc}$  and GND pins) and the corresponding drivers supplies (to be connected between HVIC  $V_{cc}$  and  $V_{ss}=COM$ ) pins.

Normally high  $di/dt$  occurs at low side switch turn on. This causes voltage spikes at low side IGBT emitter node, because of the inductive impedance  $Z_l$ , and the system must be robust to this.

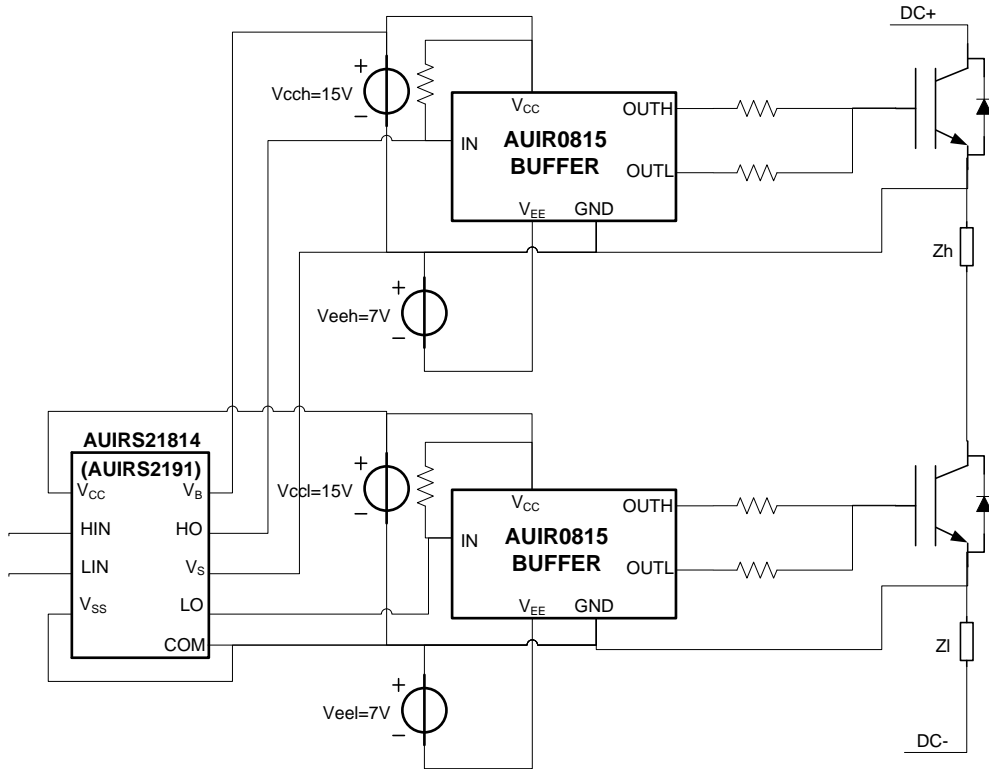
A better immunity to the above transients can be obtained using one separate low side DC power supply for each low side.

**Example 1:** using the AUIRS2181, high and low side driver with COM and no VSS pin.



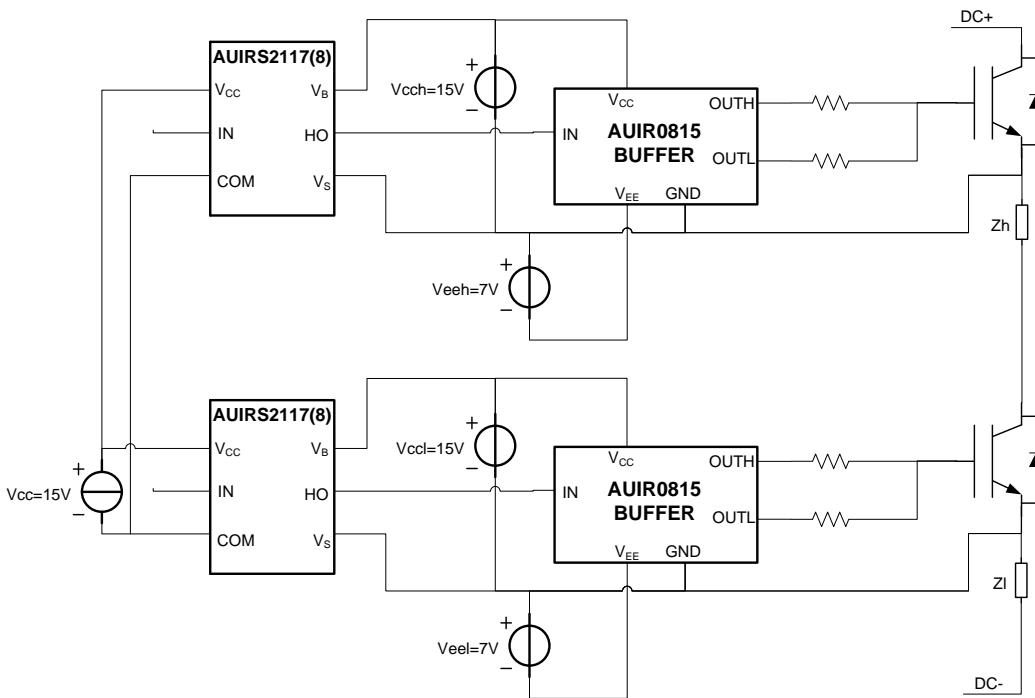
Example 1

**Example 2:** using the AUIRS21814 (or the AUIRS2191), high and low side driver with COM pin and VSS pin.



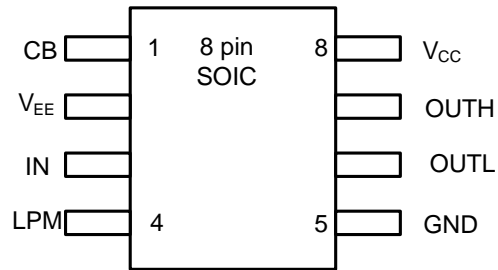
Example 2

**Example 3:** using the AUIRS2117(8), single channel driver. COM can be shorted to the Vs of the low side.



Example 3

## Lead Assignments

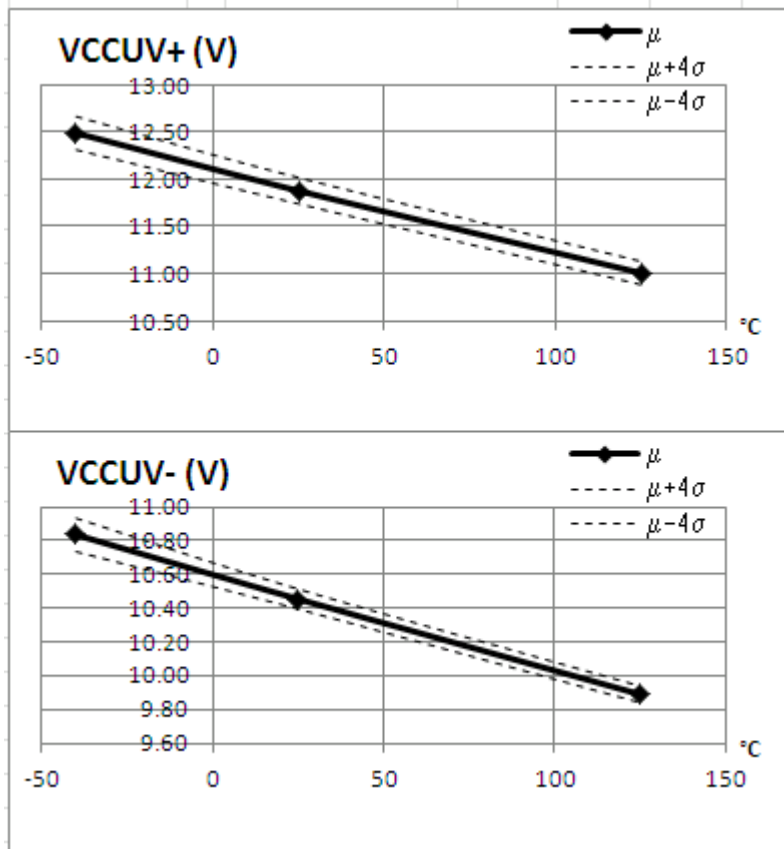


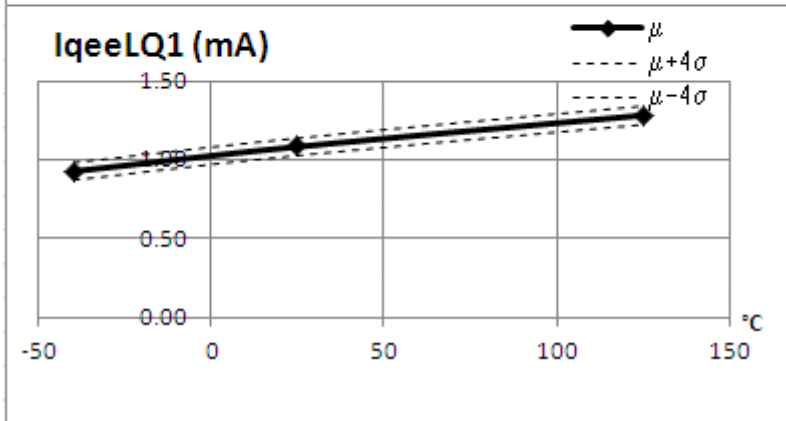
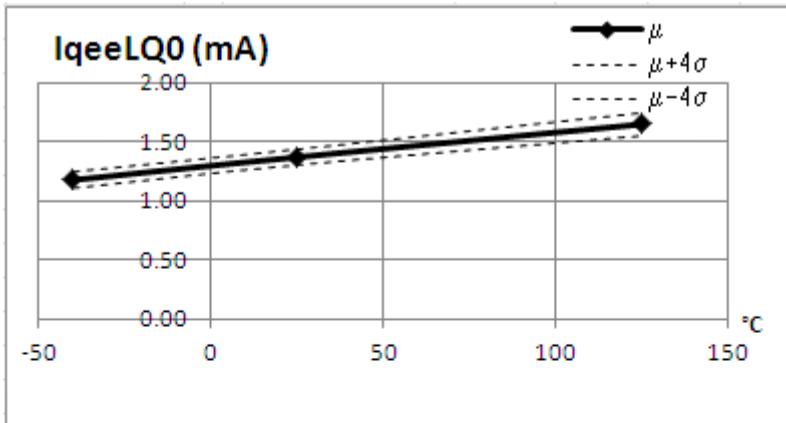
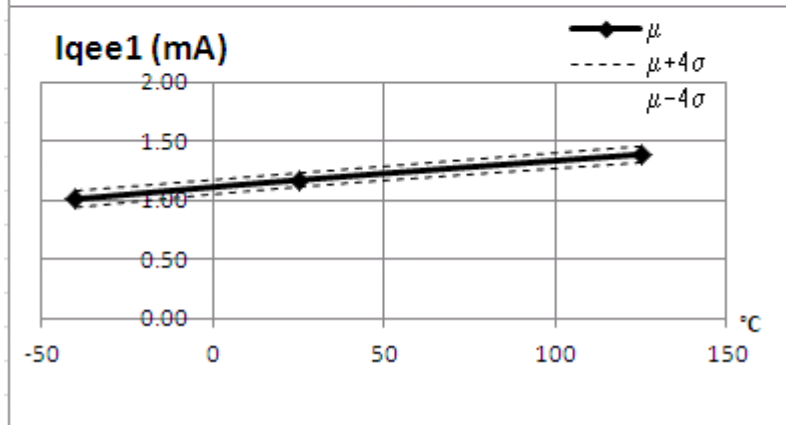
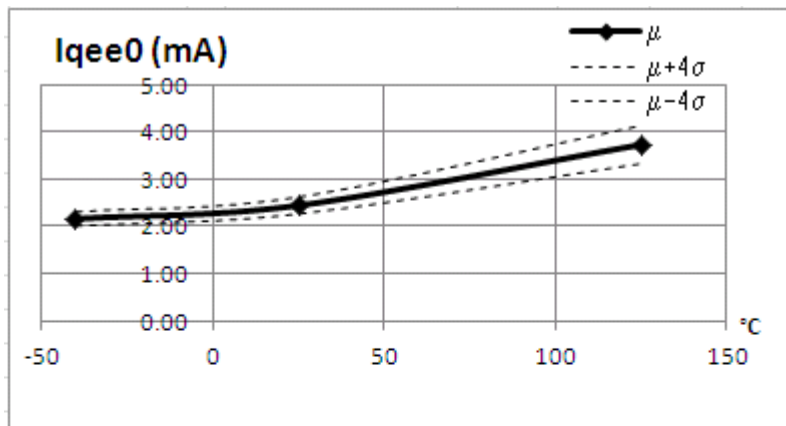
## Lead Definitions

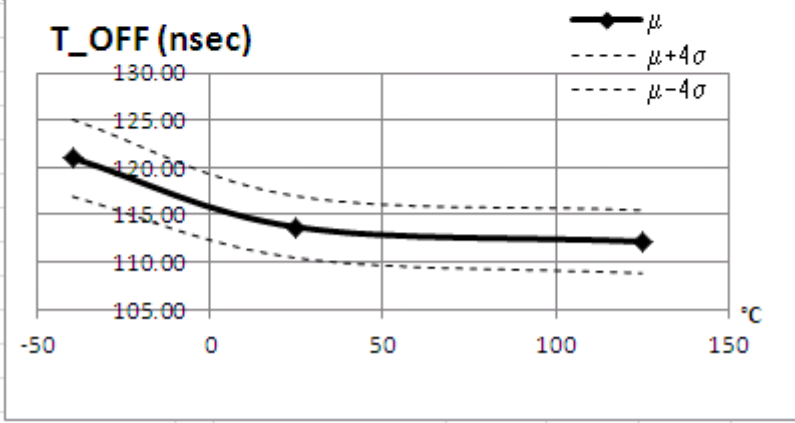
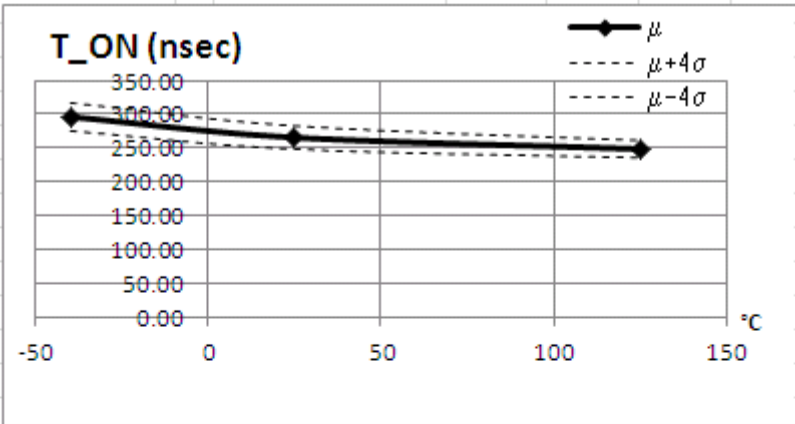
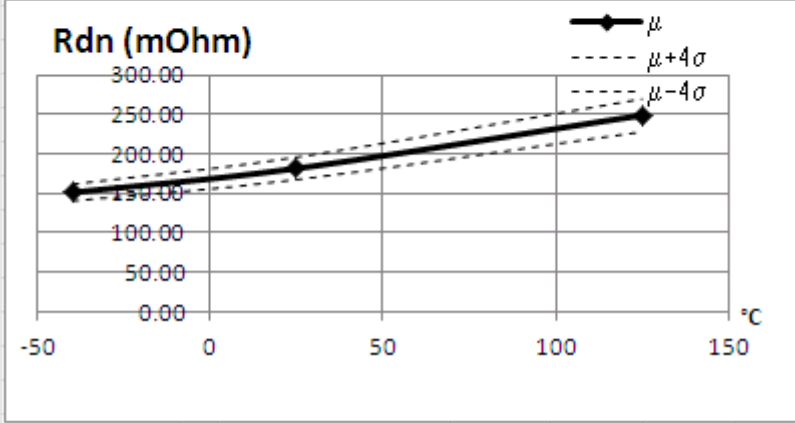
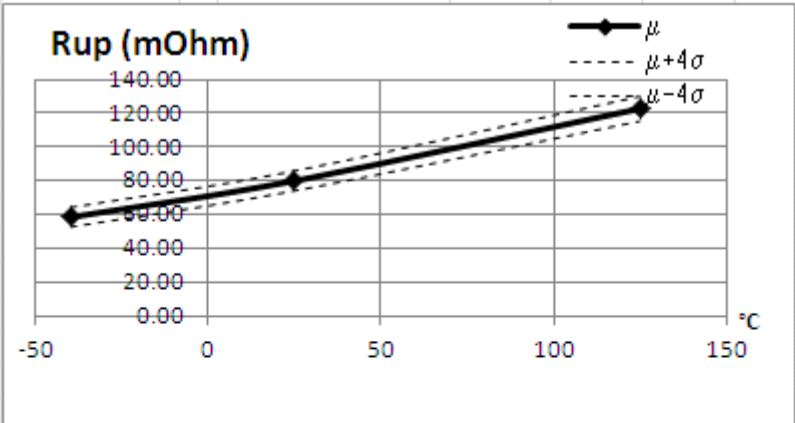
Symbol	Description
V <sub>CC</sub>	Positive supply
IN	Logic input for OUT
LPM	Logic input, for Low Power Mode: LPM=0 activates the Low Quiescent Current Mode
GND	Ground
OUTH	Power Output (pull up)
OUTL	Power Output (pull down)
C <sub>B</sub>	Boot capacitor
V <sub>EE</sub>	Negative supply pin (short to GND in case of single supply operation)

## Parameter Temperature Trends

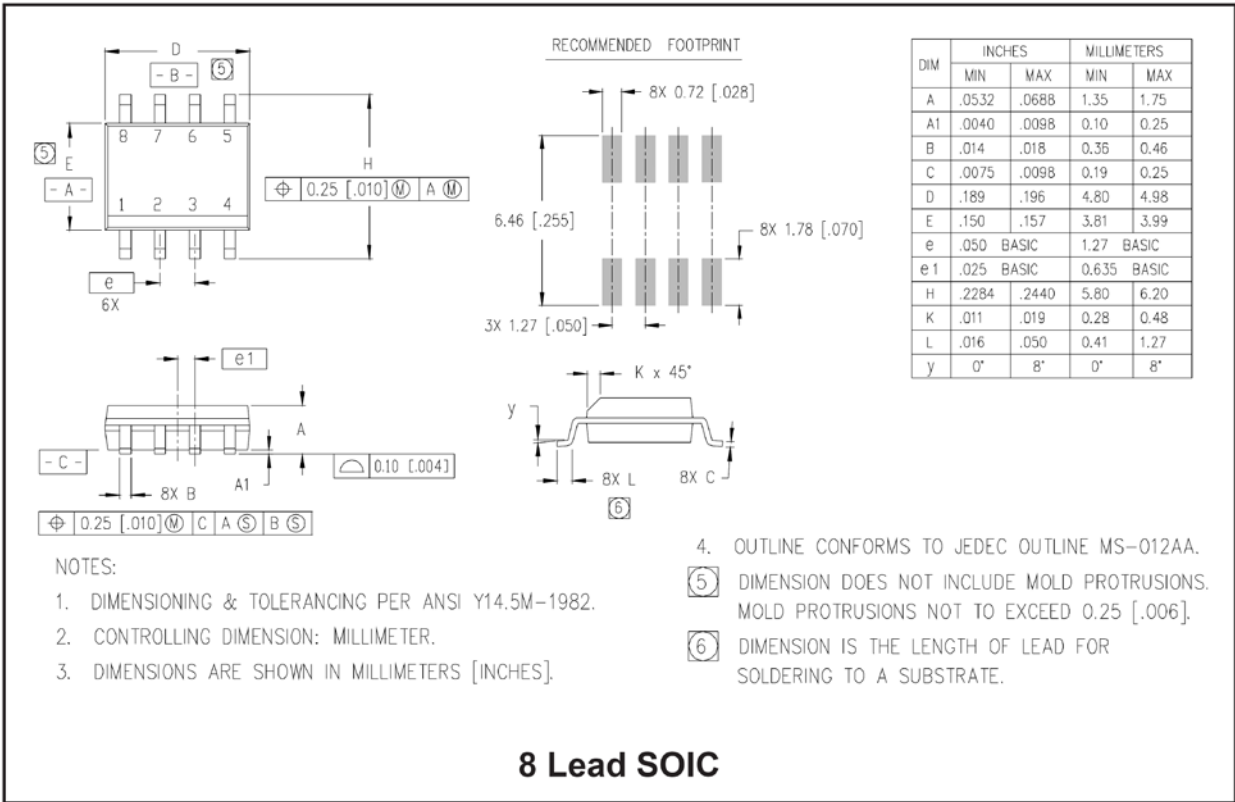
Figures illustrated in this chapter provide information on the experimental performance of the IC. The line plotted in each figure is generated from actual lab data. A large number of individual samples were tested at three temperatures (-40 °C, 25 °C, and 125 °C) in order to generate the experimental curve. The line consists of three data points (one data point at each of the tested temperatures) that have been connected together to illustrate the understood trend. The individual data points on the curve were determined by calculating the averaged experimental value of the parameter (for a given temperature).

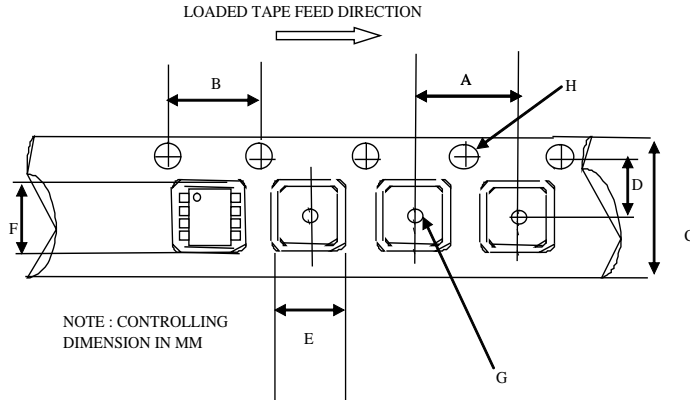




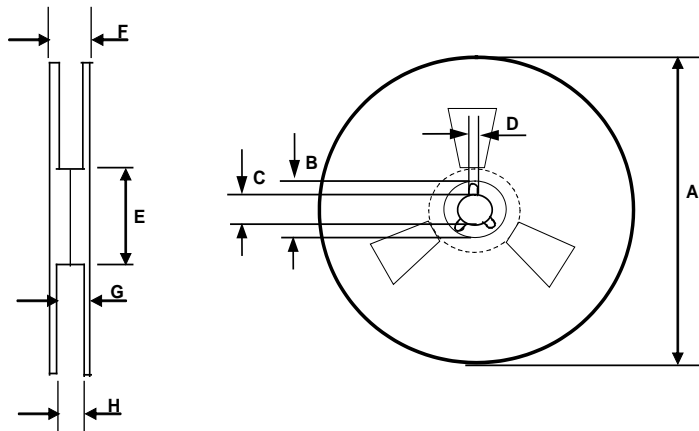


## Case Outline



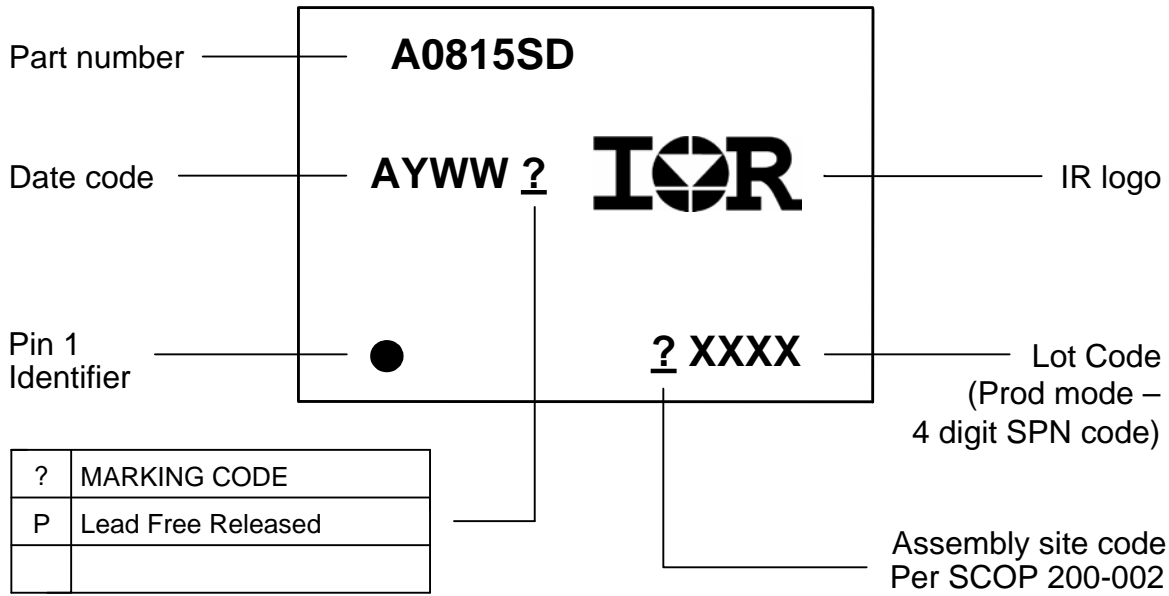
**Tape and Reel: SOIC8**

**CARRIER TAPE DIMENSION FOR 8SOICN**

Code	Metric		Imperial	
	Min	Max	Min	Max
A	7.90	8.10	0.311	0.318
B	3.90	4.10	0.153	0.161
C	11.70	12.30	0.46	0.484
D	5.45	5.55	0.214	0.218
E	6.30	6.50	0.248	0.255
F	5.10	5.30	0.200	0.208
G	1.50	n/a	0.059	n/a
H	1.50	1.60	0.059	0.062


**REEL DIMENSIONS FOR 8SOICN**

Code	Metric		Imperial	
	Min	Max	Min	Max
A	329.60	330.25	12.976	13.001
B	20.95	21.45	0.824	0.844
C	12.80	13.20	0.503	0.519
D	1.95	2.45	0.767	0.096
E	98.00	102.00	3.858	4.015
F	n/a	18.40	n/a	0.724
G	14.50	17.10	0.570	0.673
H	12.40	14.40	0.488	0.566

## Part Marking Information



## Ordering Information

Base Part Number	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIR0815S	SOIC8	Tube/Bulk	95	AUIR0815S
		Tape and Reel	2500	AUIR0815STR

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**Revision History**

Date	Comment
Dec. 2, 2009	-V <sub>E</sub> pin name changed into V <sub>EE</sub> ; note1 modified; VEE-VCC 40V diode added in block diagram; current consumption table parameters modified;
Feb 24, 2010	St. El. Ch: I <sub>QOUTL1</sub> parameter added; I <sub>QOUTH0</sub> max=2mA; I <sub>QB</sub> max=0.5mA; I <sub>BOUTH</sub> =60mA; I <sub>QEE0</sub> max=6mA; I <sub>QEE1</sub> max=3mA; I <sub>QB</sub> definition corrected; I <sub>QEE5W</sub> value deleted; Rec. Op. Con.: Cboot=10nF..20nF AC El Char: Rise Fall time definition modified; Ssd= 100us typ
Feb 24b, 2010	Soft shutdown function removed (SSD <sub>IN</sub> /EN pin renamed EN); Rup dc max value deleted; Typ connection; I <sub>QGG</sub> and I <sub>QEEEN0</sub>
Feb 25, 2010	OUTL <sub>CLAMP</sub> function added: changes in I <sub>QOUTL1</sub> , I <sub>QEE1</sub> ; added Vcl, tcl1, tcl2
Apr 23, 2010	OUTL <sub>CLAMP</sub> function removed: I <sub>QOUTL1</sub> =1uA typ, I <sub>QEE1</sub> =3mA typ; Vcl, tcl1 and tcl2 removed. Change in EN pin functionality, now it is a low quiescent current mode input: front end page description; Abs Max Rat EN Max note added; Rec Op Cond: note added to specify pulldown 30 Ohm max for Vcc down to 3V. Static el char: change in EN and IN thresholds and Rin. I <sub>QEELQ</sub> and I <sub>QEEUV</sub> parameters introduced to specify consumption in Low Quiescent Current Mode (EN=1 or Vcc< VccUV-). Truth Table modified to define V <sub>CCUV</sub> and low quiescent current mode conditions Lead Definition modified to specify new EN function. AC Electr Char: Tr and Tf specified for Low Quiescent Current Mode.
May 15, 2010	EN pin renamed into LPM. Over temperature protection removed Block diagram: <ul style="list-style-type: none"> <li>• Diode OUTL-Vcc added,</li> <li>• IN and LPM input stage detailed drawing added.</li> </ul> Static El Char: <ul style="list-style-type: none"> <li>• IN and LPM input impedance spec modified</li> <li>• note added to define V<sub>BUV</sub>.</li> <li>• I<sub>QEELEN0</sub> parameter removed because already covered by I<sub>QEELQ</sub>,</li> <li>• I<sub>QGG</sub> Test Conditions changed from IN=0; LPM=1 into IN=X; LPM=X,</li> <li>• LPM input thresholds lowered by 1V</li> <li>• Rup renamed I<sub>PMOS</sub>.</li> </ul> Ac El Char: <ul style="list-style-type: none"> <li>• t<sub>EN</sub> parameter removed,</li> <li>• max values added for t<sub>on</sub>, t<sub>off</sub>, t<sub>r</sub>, t<sub>f</sub>.</li> </ul> Rec. Op. Cond.: GND-VEE min changed from 0V to -1V.
Jun 25, 2010	I <sub>BOUTH</sub> , I <sub>IN15</sub> , parameters change; added P <sub>WON</sub> and P <sub>WOFF</sub> parameters;
Mar 01, 2011	Update in test conditions for I <sub>OUTH</sub> , I <sub>OUTL</sub> , Rup_OUTH, Rdw_OUTL. I <sub>QEELQ</sub> split into I <sub>QEELQ0</sub> and I <sub>QEELQ1</sub> I <sub>BOUTH</sub> redefined as current flowing out from CB (and not OUTH). Truth Table corrected to show how LPM does not affect the functionality. Update of heading for absolute maximum ratings Update of chart with max f vs C. Abs Max Rat: V <sub>OUTH</sub> = Vcc-37V min; V <sub>OUTL</sub> = V <sub>EE</sub> -0.2V min. Rec Op Con: V <sub>OUTH</sub> = Vcc-30V min; V <sub>OUTH</sub> - V <sub>EE</sub> = -5V min;
Mar 02, 2011	Static and dynamic el. Char: parameter limits reviewed for matching full temp range. Values in blue are still older datasheet version target value at T=25°C. Added recommendation to avoid direct short between OUTH and OUTL. Added preliminary parameter temperature trend paragraph. I <sub>PMOS</sub> test condition corrected.
Jun 22, 2011	Vccuv thresholds modified; typ connection diagram: diode removed and snubber capacitance added; maxf vc C chart updated taking into account Cs=20nF as snubber capacitance
Jun 27, 2011	Matched delay outputs front page note deleted; Rec Op Cond Vcc-GND max changed from 20V to 30V. AC El Cher: toff typ changed from 150ns to 250ns. Vccuv+ and Toff charts modified.
Aug 26, 2011	Added paragraph explaining role of Cboot. Cs snubber capacitor added in Recommended Operating Conditions and in default test set-up. V <sub>CCUV+</sub> : Min from 10.6V to 10.2V ; V <sub>CCUV-</sub> :Min from 9.7V to 9.6V ; V <sub>CCUVH</sub> :Min from 0.8V to 0.5V ; I <sub>QEE5W</sub> : Max from 8mA to 10mA ; I <sub>QOUTH0</sub> : Max from 3mA to 3.5mA ; V <sub>INH vcc</sub> : Max from -1.5 V to -1V; V <sub>LPMH vcc</sub> : Max from -2.5 V to -1.5V; V <sub>LPMhis</sub> : Max from 1 V to 1.8V; I <sub>PMOS</sub> : Min from 10mA to 5mA; t <sub>on</sub> : Max from 380ns to 400ns; t <sub>off</sub> : Max from 300ns to 350ns; t <sub>r</sub> : Max from 150ns to 250ns;
Sep 6, 2011	Changes in typ connection recommendations; maxf vs C chart update; V <sub>LPLM vcc</sub> Min Change from -3.5V to -3.8V. Temperature charts updated.
Sept. 7, 2011	Corrected part number on header; added RoHS compliant & Automotive qualified to front page; deleted preliminary and added automotive grade on front page top header; added qual info page; added tape and reel info; added part marking; added ordering info; added important notice

Oct 10, 2011	Rec Op Cond: Added description of Vouth and Vouth-Vee
Oct 17, 2011	Rec Op Cond: added "Guaranteed by design" in note under the table; Sta. El. Char. table: $V_{CCUVH}$ Min changed from 0.5V to 0.3V. Pins: IN, LPM table: $V_{INhis}$ Max changed from 3V to 3.3V; $V_{LPMH vcc}$ Max changed from -1.5V to -1.4V AC El Char table: $t_r$ Max changed from 250ns to 260ns
Oct 19, 2011	Sta. El. Char. table: $V_{CCUVH}$ Min changed back from 0.3V to 0.5V.
Oct 26, 2011	Revised MSL rating to MSL-2
Jan 20 <sup>th</sup> , 2012	Application section added: Examples of system with HVIC
Jan 24 <sup>th</sup> , 2012	"Examples of system schematics with HVIC" modified; block diagram updated.
October 24 <sup>th</sup> 2012	Added Effect of Short 'Off' Pulses part in application info and minimum $PW_{off}$ in recommended op cond. Front page typ connection, snubber cap added. Examples of system schematics with HVIC: added pullup resistors at IN in Ex1 and Ex2